## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | WEI ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α.	US-6,368,668 B1	04-2002	Kobayashi et al.	427/376.2
	В	US-2003/0021720 A1	01-2003	Reisfeld et al.	422/4
	С	US-			
	D	US-			·
	Е	US-			
	F	US-			
	G	US-			
	н	US-			
	i	US-			
	J	US-			
	К	US-	_		
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					·
	0				·	
	P					
	σ					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>v</b>	
	W	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.